

## 9 Highlights & 7 Advantages of JT63 Series Electronic Load

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#### Parallel Operation of Multi loads

Supports up to 16 sets electronic load parallel application for high power.

Supports intelligent power allocation, making operating multi loads in parallel just as operating one high power load.

Support up to 16 loads Sync. loading & dynamic test, fit for testing multi-output power supply.

#### OCP & PMAX Detection

Automatically capture OCP.

Automatically capture Pmax.

#### Multi Loads Synchronized Control

Supporting up to 16 loads dynamic loading, satisfying the cross impact test of the multi-channel output power supply.

Master load can be any load. Without frame, it can achieve low-cost module application.

One master load can control 16 loads.

#### OVP Detection

Automatically capture OCP.

uS level OVP response time measurement.

#### Load Effect Test

Automatically test load regulation.

Automatically test the internal resistance of the power supply.

#### Vpp/Ipp/Vp+/Ip+/Vp-/Ip- Measurement

Real-time display Vpp/Ipp, directly observing PARD or oscillation amplitude.

Real-time display Vp+/Vp-/Ip+/Ip- , directly observing voltage overshoot, voltage drop and current surge.

Real-time display Vp+/Vp- , in dynamic mode, directly observing voltage overshoot/voltage drop and judge the circuit.

#### Timing Measurement

1mS accuracy timing measurement.

Supporting voltage/current waveform trigger.

Supporting external trigger input.

#### Precision High Speed Digitizing Measurement

500Khz , 4096 point , 16 bit precision digitizing waveform output.

Synchronous sampling of voltage and current.

Supporting multi trigger methods.

### **Dynamic Frequency Sweep**

Automatically capture maximum  $V_{p+}$  and minimum  $V_{p-}$ .

Automatically capture sweep frequency in worst state.

## **7 Advantages of JT63 Series Electronic Load**

### **High Speed**

#### **Full range current rising time: 10uS**

- Making the system impact resistance stronger and reliability higher.
- Making the the power supply ripple rejection ratio higher and loading more accurate.
- For the equipments with same rated current, the higher the current rising slew rate is, the higher the transient test confidence degree is.
- Making CV mode loading more stable and supporting small output capacitance CC source application (eg.chargers and LED power supply).

### **High-speed Synchronized Sampling**

#### **500Khz synchronous sampling**

- Software protection response time is shorter and system is more reliable.
- Measuring bandwidth is higher. When testing the high ripple power supply or making the dynamic loading, the confidence degree of measurement is higher.
- Synchronous sampling, loading accuracy is higher.
- Supporting transient analysis and providing more intelligent application.

### **Automatic Test Alone**

- Supporting 8 working modes and 14 measured items intelligent loading and qualification evaluation.
- Supporting 8 list files, each file with up to 50 steps automatic test.
- Supporting hardware trigger input and output.
- Supporting single step manual test.
- Supporting complete test report.

### **High-luminance & Full View Graphic Dot Matrix Screen**

- High luminance and complete view display, fit for production line.
- Big screen with graphic dot matrix.
- Adjustable illuminate, fit for different working environment.

- Personalized display, fit for different application.

### **Filtering Speed Programming--Applicable to Power Supply with High Ripple**

- 15Hz、4Hz、1Hz three filtering speed.
- 15Hz high filtering speed, ensuring fast measurement and improving production efficiency.
- 1Hz low filtering speed, ensuring the most accurate measurement in harsh environment.

### **CC Source Application in CP/CR Mode**

- CP algorithm is optional. Supporting CV source and CC source test, fit for LED power supply and chargers.

### **Automatically Detecting & Matching CC/CV Source in CR Mode**

- Specific algorithm, automatically detecting the type of the measured source and automatically matching CR algorithm.
- Special hardware topological structure, ensuring CR algorithm seamless transition.